

**Which powder material properties, laser process parameters, and part properties should be measured and documented during Metal & Polymer PBF-LB within the SPP 2122?**

## **1. POWDER MATERIALS**

### **Material Properties**

### **Measurement technique**

#### **1.a) Strongly recommended:**

Volume-weighted particle size distribution  
( $X_{10,3(0)}$ ,  $X_{50,3(0)}$ , and  $X_{90,3(0)}$ )

Optical microscopy / SEM / laser scattering  
/ laser particle imaging (combination of 2 complementary methods)

Particle shape distribution (size dependent aspect ratio)

Optical microscopy / SEM

Material composition

SEM-EDX / XRF

Flowability

Rotating drum, Ring shear tester, Hausner ratio, Powder rheometer, Zimmermann powder adhesion tester

Melting and Crystallization temperatures

DSC (10 K/min heating and cooling rate)

*If nanoparticles are used as additive:*

Nanoparticle volume load

ICP-MS / XRF / AAS

Nanoparticle size distribution

TEM / DLS / ADC

If colloidal: Nanoparticle zeta potential

Zeta Sizer

Surface coverage of nanoparticles on micropowders

SEM

Interparticle distance of nanoparticles on the surface of coated micropowders

SEM

#### **1.b) Recommended:**

Nano-composite powder surface composition

XPS, EDX

Laser Absorption and Reflectivity

Ulbricht sphere, FTIR Spectrometer

Structural information

XRD / SEM-EBSD

Melting and Crystallization

Fast-DSC

*Additionally for polymers:*

Viscosity (only for polymers)

Rheometer

Melt Flow Index (only for polymers)

MFI device

## **2. LASER PROCESS PARAMETERS:**

### **2.a) Strongly recommended:**

Laser type, laser wavelength, laser spot size ( $1/e^2$ ), relative hatch distance (hatch/spot), specific energy density (laser power per scan speed or laser power per volume), powder layer thickness, scan pattern, hatch strategy, recoating speed, atmosphere (i.e. ppm oxygen), gas flow rate

### **2. b) Recommended:**

Measuring the actual laser output power (behind optics, once per experimental series) and effective scanning speed of the system (once)

## **3. PART PROPERTIES:**

<b><u>As-built part property</u></b>	<b><u>Measurement technique</u></b>	<b><u>Responsible Group in Round-Robin studies</u></b>
<i>Both for <u>polymer</u> &amp; <u>metal</u> parts:</i>		
Composition	XRF	S. Barcikowski
Relative density		
Sectional	Optical Microscopy	F. Walther, M. Schaper
Volumetric	$\mu$ -Computed Tomography ( $\mu$ -CT)	F. Walther
Pore size & distribution		
Sectional	Optical Microscopy	M. Schaper
Volumetric	$\mu$ -CT	F. Walther
3D imaging of microstructure	FIB-SEM	H. J. Maier
Status of NPs in the microstructure	SEM, TEM	H. J. Maier
Mechanical strength	Tensile test	G.A. Luinstra, H. J. Meier
<i>Additionally for <u>polymer</u> parts:</i>		
Molecular weight	Gel Permeation Chromatography (GPC)	G.A. Luinstra
Rheology	Rheometer	G.A. Luinstra
Crystallinity	Wide Angle X-ray Scattering (WAXS), Polarized microscope	D. Drummer
<i>Additionally for <u>metal</u> parts:</i>		
Crystal orientation of grains	SEM-EBSD	M. Schaper
Hardness	Vickers Hardness Tester	H. J. Maier
Corrosion resistance	Potentiodynamic test	G. Grundmeier

**Where within the SPP 2122 can I get access to the recommended measurement techniques?**

**Measurement technique**

**Available within the SPP, e.g. through the following groups (exemplary):**

Optical Microscopy	All
Scanning Electron Microscopy (SEM)	All
Energy-dispersive X-ray spectroscopy (EDX)	All
Electron backscatter diffraction (EBSD)	M. Schaper, W. Theisen
Laser Diffraction	A. Kwade, M. Lang, J. Schmidt, G. Luinstra, M. Petermann
Dynamic Particle Image Analysis (shape & size distribution)	F. Walter
Dynamic Light Scattering (DLS)	A. Kwade, S. Barcikowski
Analytical Disc Centrifugation (ADC)	A. Kwade, S. Barcikowski
Differential Scanning Calorimetry (DSC)	(almost) All
Differential Fast Scanning Calorimetry (DFSC)	O. Keßler
Zeta Sizer	A.Kwade, S. Barcikowski
Rotating Drum	A. Kwade, J. Sehart
Ring Shear Tester	A. Kwade, J. Schmidt
Powder rheometer	J. Sehart
X-Ray Fluorescence (XRF)	S. Barcikowski
X-Ray Photoelectron Spectroscopy (XPS)	S. Barcikowski
X-Ray Diffraction (XRD)	(almost) all
MFI/Rheometer	M. Lang, C. Bierwisch, J. Schmidt
FTIR Spectrometer (with heating up to 1000°C)	J. Sehart
Laser absorbtivity	M. Schmidt